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INDUSTRY NEWS

nPoint, Inc., the global leader in ultra-precision motion and control nanopositioners for nanoscale research and manufacturing, has announced a new member of its PiezoMAX(TM) product line. The N-XYZ100B is used for microscopy applications that require transmitted light through the sample, such as the traditional inverted optical microscope, confocal microscope, and near-field scanning optical microscope (NSOM). The aperture enables a light beam to pass through the sample, while the nanopositioner allows the sample to be moved and controlled within nanometer range.Contact: Katerina Moloni, VP Marketing of nPoint, Inc., 608-204-8756, or katerina.moloni@npoint.com.

Aperio's ScanScope™ Eliminates Need for Microscope. Aperio Technologies announces the release of new software for viewing multi-gigabyte digital images (virtual slides) directly on a monitor from anywhere in the world. "Our software makes it possible – for the first time – to efficiently view multi-gigabyte images across any network" remarked Dirk Soenksen, Chief Executive Officer of Aperio Technologies. "When used in telepathology or education, this software eliminates the need to send glass slides or a pathologist from one location to another, providing significant savings to our customers. Remote diagnosis by an expert can be made immediately." Contact: Dirk Soenksen, Phone: (760) 539-1100 info@aperiotech.com.

Microscopy/Marketing & Education, Inc. (MME) proudly announces the launch of the first industry baseline to track quarterly changes in the EDX/WDS segment of the worldwide microscopy market. Charter members include the four industry leaders: Ametek/Edax, Oxford Instruments, Princeton GammaTech, and ThermoNoran. Additionally, key smaller firms have joined for a special once-a-year minority report. Contact: Barbara Foster, 413-746-6931, bfoster@mme1.com.

Tamar Technology introduces a new, patented transmitted light illuminator to replace traditional microscopy methodology, according to David Grant, president of Thousand Oaks, Californiabased Tamar Technology. Tamar's EtherGlow, developed at the University of California, Irvine's Beckman Laser Institute, uses a patented technology to produce a light source that results in a flat plate illuminator. This technology replaces Kohler transmitted illumination. EtherGlow provides instant and perfect matching of condenser and objective, elimination of Fresnel diffraction rings, improved contrast and a shortened depth of focus similar to a confocal microscope. Contact: Gregg Kleinberg, Tamar Technology 619-994-5536.

Pacific Nanotechnology Unveils Nano-R Atomic Force, the first atomic force microscope (AFM) to combine high-performance, ease-of-use, and affordability in a single instrument. Advanced features in the Nano-R stage are designed to make it both easy to use and extremely accurate. The Nano-R includes SPMCockpit(TM) software that offers both AFM image acquisition and image analysis capabilities. The image capture software has an EZMode(TM) option for novice users and X'Pert(TM) option for advanced users. It includes 2-D and 3-D display modes as well as the most common analysis techniques, such as line profiles. Contact: Paul West 714-258-0190, or pwest@pacificnanotech.com

PerkinElmer Instruments introduced enhanced software for the AutoIMAGE[™] Fourier-transform infrared (FT-IR) Microscope range, allowing users in analytical, research and development, and forensic science laboratories to solve problems faster, decreasing time-to-market, and reducing costs. The new AutoIMAGE V5.00 software offers an extended suite of powerful data processing algorithms and an enhanced 3-D data display, increasing the analyst's ability to extract complex molecular information from challenging samples. Laboratories can now employ techniques in which a target spectrum can be matched against, or subtracted from, every point in a chemical map to enhance small differences in composition. The interactive 3-D surface projections allow product defects to be visualized more quickly, saving time and simplifying analysis. In addition, chemical maps can be overlaid, enabling the distribution of multiple components across a sample to be seen easily. For further information: Stephanie Wasco, PerkinElmer Instruments (203) 402-1700.

Asylum Research announces a new advanced nanolithography and manipulation feature, MicroAngelo, that comes standard with all its MFP-3D AFM systems. MicroAngelo's precision and accuracy is derived from three powerful features inherent in the MFP-3D systemthe fully-digital controller, Igor Pro Software, and the patent-pending Nanopositioning (NPS) System. The NPS' sensored, closed loop operation in all three axes provides sub-nanometer resolution over the entire 100µm scan range with noise levels that are the lowest in the industry. This allows repeatable imaging, quantitative feature measurement, reliable and accurate imaging offsets, and quantitative positioning for manipulation and lithography. Contact: Terry Mehr, terry@AsylumResearch.com, 805-685-7077



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